

Marlon L. Walker

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Marlon Walker's research interests lie in the direction of non-destructive surface characterization, including "soft-surfaces" such as self-assembled monolayers (SAMs) and thin polymer films. Recent work involved using *in situ* spectroscopic ellipsometry to explore the interactions of certain additives critical to the copper electrodeposition process applicable to microelectronic circuitry. Current efforts center around surface modification methodologies, and include development and characterization of oligo(ethylene oxide)-based self-assembled monolayers that resist protein adsorption. He is also heavily involved in STEM-related outreach efforts to organizations such as NOBCCChE.